

## 1. Product information

Supplier : JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

|                    |                  |
|--------------------|------------------|
| Part Number :      | CJP130SN10       |
| Package Type :     | TO-220-3L-C      |
| Part Description : | 100V THDs/MOSFET |
| Report Date:       | April-25         |

## 2. Reliability Test Results : PASS

| Test Item                                             | Test condition                                                                                                                                                   | Duration                     | Fail Quantity / S.S |
|-------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------|------------------------------|---------------------|
| Pre-and post-stress Electrical test                   | Ta=25°C                                                                                                                                                          | NA                           | All parts           |
| <b>PC</b><br>Precondition(For SMD Package Only)       | JESD22-A113F/J-STD-020<br>1.Bake:125°C.<br>2.Soak:<br>85°C85%RH,168hrs MSL1<br>or<br>30°C60%RH,192hrs MSL3<br>3.Reflow 3Cycles Max 260°C<br>4.all samples E-Test | >168Hours<br>or<br>>192Hours | 0 / 308*3           |
| <b>TCT</b><br>Temperature Cycling Test                | JESD22 -A104<br>-55°C/15min 150°C/15min                                                                                                                          | 1000cycles                   | 0 / 77*3            |
| <b>AC</b><br>Autoclave                                | JESD22-A102<br>121°C, 100%RH                                                                                                                                     | 96Hours                      | 0 / 77*3            |
| <b>UHA</b><br>Unbiased Highly Accelerated Stress Test | JESD22-A118<br>130°C, 85%RH                                                                                                                                      | NA                           | NA                  |
| <b>TH</b><br>High Humidity &Temp Test                 | JESD22-A101<br>85°C 85%RH                                                                                                                                        | 1000Hours                    | 0 / 77*3            |
| <b>HT</b><br>High Temperature Storage Test            | JESD22 -A103<br>T=Tstg max                                                                                                                                       | 1000Hours                    | 0 / 77*3            |
| <b>H3TRB</b><br>High Humidity &Temp . Bias Test       | JESD22-A101<br>85°C 85%RH VDS*80% VR<=100V Max                                                                                                                   | NA                           | NA                  |
| <b>HAST</b><br>Highly Accelerated Stress Test         | JESD22-A110<br>130°C 85%RH VDS*80% VR≤42V Max                                                                                                                    | 96Hours                      | 0 / 77*3            |
| <b>HTRB</b><br>High Temperature Revers Bias Test      | JESD22 -A108<br>Tj(max) @VDS *80%                                                                                                                                | 1000Hours                    | 0 / 77*3            |
| <b>HTGB</b><br>High Temperature Gate Bias Test        | JESD22 -A108<br>Tj(max) VR=BVGS*100%                                                                                                                             | 1000Hours                    | 0 / 77*3            |
| <b>IOL</b><br>Intermittent Operational Life           | MIL-STD-750D Method 1037<br>△Tj≥100°C On/Off:2min                                                                                                                | 15000Cycle                   | 0 / 77*3            |
| <b>RSH</b><br>Resistance to Solder Heat test          | JESD22-A111B<br>260°C±5°C, 10(+2,-0)Seconds                                                                                                                      | NA                           | 0 / 30*3            |
| <b>SD</b><br>Solderability                            | J-STD-002<br>Steam aging:93°C 8hour 2.245°C 3~5s                                                                                                                 | NA                           | 0 / 10*3            |

### Notes:

1. Either H3TRB or HAST for reliability test.
2. Either AC or UHA for reliability test.
3. Detailed MSL of the product refers to the MSL Report.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report